

Search Notes

Application/Control No.

10/721,380

Examiner

German Viana Di Prisco

Applicant(s)/Patent under
Reexamination

KIM, TAE-KON

Art Unit

2616

SEARCHED

Class	Subclass	Date	Examiner
370	908	9/26/2007	GV

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Image and keyword search in USPAT, US-PGPUB, DERWENT,EPO,JPO and IBM_TDB (see attached search strategy)	9/26/2007	GV
Inventor name and Assignee search in PALM ExPO and EAST	9/26/2007	GV
IEEE Xplore(<a href="http://ieeexplore.ieee.org/Xplor
e/DynWel.jsp">http://ieeexplore.ieee.org/Xplor e/DynWel.jsp)	9/26/2007	GV
Korea Institute of Patent Information http://eng.kipris.or.kr/	9/26/2007	GV
Consulted with Rafael Perez-Gutierrez and Ken Vanderpuye	9/26/2007	GV
EPO Database(http://eo.espacenet.com)	9/26/2007	GV
(point adj coordinator or pc) and (cfp or (contention adj free adj period)) and queue	9/26/2007	GV